
CONTENTS

<i>Preface</i>	vii
<i>Acknowledgements</i>	viii
1 Introduction to electron beam instruments	1
1.1 Introduction	1
1.2 Basic properties of electron emitters	1
1.3 Electron optics, electron lenses and deflection systems	7
References	18
2 Electron–specimen interactions	19
2.1 Introduction	19
2.2 Elastically scattered electrons	19
2.3 Inelastically scattered electrons	24
2.4 Generation of X-rays	26
2.5 Generation of Auger electrons	35
2.6 Generation of electron beam induced current and cathodoluminescence signals	37
References	38
3 Layout and operational modes of electron beam instruments	39
3.1 Transmission electron microscopy	39
3.2 Scanning electron microscopy	44
3.3 Scanning transmission electron microscopy	50
3.4 Auger electron spectroscopy	53
3.5 Electron microprobe analysis	56
3.6 X-ray spectrometers	57
3.7 Electron spectrometers	61
References	64
4 Interpretation of diffraction information	65
4.1 Introduction	65
4.2 Analysis of electron diffraction patterns	65

4.3 Interpretation of diffraction maxima associated with phase transformations and magnetic samples	101
4.4 Interpretation of diffraction patterns from twinned crystals	108
4.5 Interpretation of channelling patterns and backscattered electron patterns in scanning electron microscopy	109
References	112
5 Analysis of micrographs in TEM, STEM, HREM and SEM	113
5.1 Introduction	113
5.2 Theories of diffraction contrast in transmission electron microscopy	114
5.3 Analysis of images in transmission electron microscopy	119
5.4 Influence of electron optical conditions on images in TEM and STEM	143
5.5 Interpretation of high resolution electron microscopy images	144
5.6 Interpretation of scanning electron microscopy images	147
References	151
6 Interpretation of analytical data	153
6.1 Interpretation of X-ray data	153
6.2 Interpretation of data from thin samples	153
6.3 Interpretation of X-ray data from bulk samples	162
6.4 Interpretation of electron energy loss spectra	163
6.5 Interpretation of Auger spectra	169
6.6 Spatial resolution of analysis	175
References	177
Appendix A The reciprocal lattice	179
Appendix B Interplanar distances and angles in crystals. Cell volumes. Diffraction group symmetries	184
Appendix C Kikuchi maps, standard diffraction patterns and extinction distances	189
Appendix D Stereomicroscopy and trace analysis	198
Appendix E Tables of X-ray and EELS energies	200
<i>Index</i>	209